## Notice of References Cited Application/Control No. 10/785,048 Examiner Dustin Nguyen Applicant(s)/Patent Under Reexamination DATE ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,155,532	12-2006	Schoenblum, Joel W.	709/231
*	В	US-7,006,526	02-2006	Biederman, Daniel C.	· 370/466
*	С	US-2003/0126294	07-2003	Thorsteinson et al.	709/247
*	D	US-6,934,288	08-2005	Dempo, Hiroshi	370/394
*	Е	US-6,973,097	12-2005	Donzis et al.	370/470
*	F	US-7,228,422	06-2007	Morioka et al.	713/171
*	G	US-2004/0174824	09-2004	Ohta et al.	370/252
*	Н	US-2003/0229778	12-2003	Oesterreicher et al.	713/150
*	ı	US-2005/0237434	10-2005	Takatori et al.	348/725
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s	,				·
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	·
	٧	
	w	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.